

Epitaxial silicon detectors irradiated with protons and neutrons

Monday 12 November 2007 16:30 (20 minutes)

A series of epitaxial detectors of 150 μm thickness produced by different producers (IRST, CNM, HIP) will be compared to each other (CV,IV,CCE) after proton and neutron irradiation.

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Session Classification: Pad Detector Characterization & Defect Engineering

Track Classification: Defect Engineering and Pad Detector Characterization